REMARKS

The Examiner is thanked for the thorough examination of the present application. The Office Action, however, tentatively rejected all claims. In response, Applicant submits the foregoing amendments and the following remarks. Specifically, in response to the Office Action, claims 1, 8, 11, 12, 14-16, 23, 26, 27, 29-34, 38, 41, 42, 44, 45 and 53 are amended, and claims 5-7, 9, 10, 13, 20-22, 24, 25, 28, 35-37, 39, 40, 43, 46-52, 54 and 55 are cancelled. These amendments render all outstanding rejections moot, as various features and limitations have been added to every independent claim. As such features were not embodied in the outstanding rejections, the amended features render the rejections moot. Applicant respectfully requests reconsideration and withdrawal of the rejections.

Amendment to the Specification

Applicant has made a minor, cosmetic amendment to the specification. This amendment adds no new matter to the application.

Rejections under 35 U.S.C 112

The Office Action rejected claims 8, 23, and 38 under 35 U.S.C. § 112, second paragraph, as allegedly being indefinite. Applicant has amended each of these claims to address and overcome these rejections. Accordingly, the rejections should be withdrawn.

Rejections under 35 U.S.C 102(e)

Claims 1-6, 9-12, 16-21, 24-27, 31-36, 39-42 and 46-55 stand rejected under 35

U.S.C 102(e) as allegedly being anticipated by US PAT 7,237,266 to Aaron. Applicant

respectfully requests reconsideration and withdrawal of these rejections.

With respect to independent claims 1, 16, 31 and 53, these claims respectively

recite:

> 1. A reliability assessment system for assessing a reliability of
> a semiconductor product, comprising:
> an interface to *receive a selection of an assessment item for the
> semiconductor product*, and input items corresponding to
> the assessment item, *wherein the assessment item
> comprises a manufacturing process for the
> semiconductor product*; and
> an assessment engine to *perform a reliability assessment for the
> semiconductor product toward the assessment item
> according to the input items and the manufacturing
> process*, generate a result of the reliability assessment, and
> display the result on the interface, wherein the result
> comprises at least one output item corresponding to the
> assessment item.

> 16. A computerized reliability assessment method for assessing
> a reliability of a semiconductor product, comprising the steps of:
> *receiving a selection of an assessment item for the
> semiconductor product*, and input items corresponding to
> the assessment item through a web-based interface,
> *wherein the assessment item comprises a
> manufacturing process for the semiconductor product*;
> *performing a reliability assessment for the semiconductor
> product toward the assessment item according to the
> input items and the manufacturing process*; and
> generating a result of the reliability assessment, wherein the result
> comprises at least one output item corresponding to the
> assessment item.

> 31. A machine-readable storage medium storing a computer
> program which, when executed, directs a computer to perform a method
> of reliability assessment for assessing a reliability of a semiconductor
> product, comprising the steps of:

>> *receiving a selection of an assessment item for the*
>>> *semiconductor product*, and input items corresponding to
>>> the assessment item through a web-based interface,
>>> *wherein the assessment item comprises a*
>>> *manufacturing process for the semiconductor product*;
>> *performing a reliability assessment for the semiconductor*
>>> *product toward the assessment item according to the*
>>> *input items and the manufacturing process*; and
>> generating a result of the reliability assessment, wherein the result
>>> comprises at least one output item corresponding to the
>>> assessment item.

>> 53.   A set of application program interfaces embodied on a
> computer-readable medium for execution on a computer in conjunction
> with an application program that performs a reliability assessment for
> assessing a reliability of a semiconductor product, comprising:
>> a first interface to *receive a selection of an assessment item for*
>>> *the semiconductor product*, and input items corresponding
>>> to the assessment item of a reliability inquiry; and
>> a second interface to display a result of the reliability assessment, in
>>> which the result comprises at least one output item
>>> corresponding to the assessment item, and *the result is*
>>> *generated according to a reliability assessment for the*
>>> *semiconductor product toward the assessment item*
>>> *based on the input items and the manufacturing*
>>> *process*.

(*Emphasis added*). Independent claims 1, 16, 31, and 53 patently define over Aaron for

at least the reason that Aaron fails to disclose or suggest the features emphasized

above.

First, the Aaron reference relates to computer and network management and

troubleshooting systems for *retrieving related vulnerability information*. More

particularly, *the Aaron reference is an information retrieval system.* The claimed

embodiments, in contrast, relate to assessment of reliability for *semiconductor*

products. A user can input an assessment item and related data for simulating the

reliability of a semiconductor product, and returning results corresponding to the

assessment item. Simply stated, the Aaron reference and the present application are in different technology fields and for different objectives.

In col. 9, lines 54-56 of the Aaron reference, *a user must actively input policy information to assist in identifying security and/or reliability related vulnerabilities of computer and/or network systems*. In the systems and methods of the present application, however, *selections of assessment items for a semiconductor product are provided for assisting user input*, and one of the selections can be selected by the user. Nowhere in the Aaron reference does it teach that selections are provided for input. Additionally, it is clear that the purpose of *the Aaron reference is to identify and retrieve security and/or reliability related vulnerabilities of computer and/or network systems.* In the present application, however, a purpose *is to simulate the reliability assessment of a semiconductor product, and return related results*. The purposes and the targets for reliability assessment are vastly different.

Further, in the Aaron reference, the vulnerability information is retrieved by **keyword matching** between the policy information input by the user and the vulnerability information recorded in the database. In the systems and methods of the present application, however, the reliability assessment for the semiconductor product toward the assessment item is performed according to the input items and **the manufacturing process corresponding to the semiconductor product**. Simply stated, the information retrieval manners of the two applications are different.

Since Aaron fails to teach or suggest the combination of claimed features of the independent claims, claims 1, 16, 31 and 53 are patentable over the cited reference.

Insofar as all remaining claims depend from either claim 1, 16, 31, or 53, all pending claims patently define over Aaron.

CONCLUSION

In view of the foregoing, it is believed that all pending claims are in proper condition for allowance. If the Examiner believes that a telephone conference would expedite the examination of the above-identified patent application, the Examiner is invited to call the undersigned.

No fee is believed to be due in connection with this submission. If, however, any fee is deemed to be payable, you are hereby authorized to charge any such fee to Deposit Account No. 20-0778.

Respectfully submitted,

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By: _____

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